



FOR IMMEDIATE RELEASE

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**AEHR TEST SYSTEMS RECEIVES FOLLOW-ON MAX ORDERS
FROM A MAJOR IC MANUFACTURER**

Fremont, CA (September 1, 2005) – Aehr Test Systems (Nasdaq: AEHR), a leading supplier of semiconductor test and burn-in equipment, today announced it has received follow-on orders from a major IC manufacturer totaling approximately \$5 million for its MAX monitored burn-in systems. The systems are scheduled to ship during the next two quarters.

This customer presently has an installed base of MAX3 and MAX4 systems at various locations world-wide. These systems will provide additional production capacity for monitored burn-in of advanced logic devices.

“We are pleased to continue our relationship with this major IC manufacturer,” said Greg Perkins, vice president of world-wide sales and service at Aehr Test Systems. “We believe the MAX systems continue to be a key part of their world-wide burn-in strategy and Aehr’s demonstrated ability to support all their locations is extremely important. We also believe the follow-on MAX system orders demonstrate our ability to provide a reliable, cost-effective production burn-in solution for logic manufacturers. The MAX systems provide functional test during burn-in, resulting in improved burn-in screening and device quality.”

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing DRAM and logic integrated circuits and has an installed base of more than 2,500 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX™, MTX, MAX3 and MAX4 systems, and the DiePak® carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company’s Web site at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test’s products. Actual results may vary from projected results. These risks and uncertainties include, without limitation,

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acceptance by customers of the MAX technology, acceptance by customers of the MAX systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K and 10-Q reports and other reports from time to time filed with the Securities and Exchange Commission (SEC) for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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